

Notice of References Cited	Application/Control No. 10/081,021	Applicant(s)/Patent Under Reexamination SAMN, JONATHAN	
	Examiner Etienne P LeRoux	Art Unit 2161	Page 1 of 1.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0049751	04-2002	Chen et al.	707/3
	B	US-2004/0078388	04-2004	Melman, Haim Zvi	707/104.1
	C	US-			
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